

Electromagnetic fields in contemporary office workplaces

Koppel, Tarmo; Tasa, T.; **Tint, Piia** Agronomy research 2013 / p. 421-434 : ill

<https://www.cabidigitallibrary.org/doi/pdf/10.5555/20133221144> [Journal metrics at Scopus](#) [Article at Scopus](#)

On BTI aging rejuvenation in memory address decoders

Gürsoy, Cemil Cem; Kraak, Daniel; **Ahmed, Foisal**; Taouil, Mottaqiallah; **Jenihhin, Maksim**; Hamdioui, Said 2022 IEEE 23rd Latin American Test Symposium, LATS 2022 2022 / Code 184360 <https://doi.org/10.1109/LATS57337.2022.9936940>

On NBTI-induced aging analysis in IEEE 1687 reconfigurable scan networks

Damljanovic, Aleksa; Squillero, Giovanni; **Gürsoy, Cemil Cem**; **Jenihhin, Maksim** VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 335-340 : ill <https://doi.org/10.1109/VLSI-SoC.2019.8920313>

Practical indicators for risk of airborne transmission in shared indoor environments and their application to COVID-19 outbreaks

Peng, Zhang; Pineda Rojas, Andrea L.; Kropff, Emilio; **Kurnitski, Jarek** Environmental science & technology 2022 / p. 1125-1137 <https://doi.org/10.1021/acs.est.1c06531> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journalmetrics at WOS](#) [Article at WOS](#)

Security risk management in the aviation turnaround sector

Matulevičius, Raimundas; **Norta, Alexander**; **Udokwu, Chibuzor**; **Nõukas, Rein** Future Data and Security Engineering : Third International Conference, FDSE 2016, Can Tho City, Vietnam, November 23-25, 2016 : proceedings 2016 / p. 119-140 : ill

https://doi.org/10.1007/978-3-319-48057-2_8 [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Conference Proceedings at WOS](#) [Article at WOS](#)

Shielding inbound microwave electromagnetic radiation

Koppel, Tarmo; Haldre, Heldur 56th International Riga Technical University Conference "Scientific Conference on Economics and Entrepreneurship SCEE'2015" : proceedings 2015 / p. 151-153 : tab

Software-based mitigation for memory address decoder aging

Kraak, D. H. P.; **Gürsoy, Cemil Cem**; **Jenihhin, Maksim**; **Raik, Jaan** LATS 2019 : 20th IEEE Latin American Test Symposium : Santiago, Chile, March 11th - 13th 2019 2019 / 6 p. : ill <https://doi.org/10.1109/LATW.2019.8704595>